

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/756,575	SMITH, EDWIN DEREK	
Examiner		KIEU-OANH T BUI	Art Unit	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,522,347 B1	02-2003	Tsuji et al.	715/848
	B	US-6,731,326 B1	05-2004	Bettinardi, Edward R.	348/63
	C	US-6,526,296 B1	02-2003	Niemenen, Timo T.	455/575.3
	D	US-6,009,336	12-1999	Harris et al.	455/566
	E	US-6,385,772 B1	05-2002	Courtney, Jonathan D.	725/105
	F	US-6,487,396	11-2002	Sassi, Heikki	455/90.1
	G	US-6,631,522 B1	10-2003	Erdelyi, David	725/53
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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